



65 Amps, 60 Volts N-CHANNEL POWER MOSFET

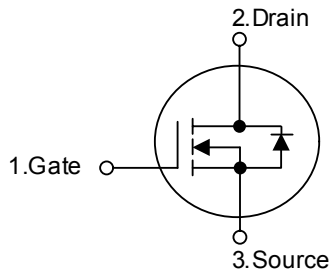
DESCRIPTION

This MOSFET process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency, high-frequency isolated DC-DC converters for Telecom and Computer applications. It is also intended for any applications with low gate drive requirements.

FEATURES

- TYPICAL $R_{DS(on)} = 0.016\Omega$
- EXCEPTIONAL dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- LOW THRESHOLD DRIVE

SYMBOL

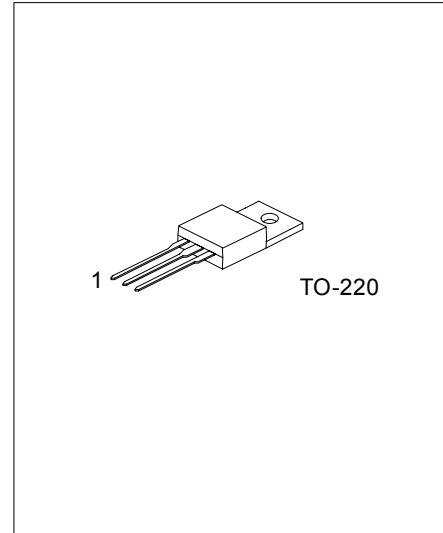


ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | Value | Unit |
|-------------------|---|------------|---------------------|
| V_{DS} | Drain-source Voltage ($V_{GS} = 0$) | 60 | V |
| V_{DGR} | Drain-gate Voltage ($R_{GS} = 20\text{ k}\Omega$) | 60 | V |
| V_{GS} | Gate- source Voltage | ± 20 | V |
| I_D | Drain Current (continuous) at $T_C = 25^\circ\text{C}$ | 65 | A |
| I_D | Drain Current (continuous) at $T_C = 100^\circ\text{C}$ | 42 | A |
| $I_{DM}(\bullet)$ | Drain Current (pulsed) | 260 | A |
| P_{tot} | Total Dissipation at $T_C = 25^\circ\text{C}$ | 110 | W |
| | Derating Factor | 0.73 | W/ $^\circ\text{C}$ |
| dv/dt (1) | Peak Diode Recovery voltage slope | 4 | V/ns |
| E_{AS} (2) | Single Pulse Avalanche Energy | 360 | mJ |
| T_{stg} | Storage Temperature | -65 to 175 | $^\circ\text{C}$ |
| T_j | Max. Operating Junction Temperature | | |

(\bullet) Pulse width limited by safe operating area.

(1) $I_{SD} \leq 65\text{A}$, $di/dt \leq 400\text{A}/\mu\text{s}$, $V_{DD} \leq 24\text{V}$, $T_j \leq T_{JMAX}$.



*Pb-free plating product number: 65N60

■ THERMAL DATA

| | | | | |
|----------------|--|-----|------|------|
| Rthj-case | Thermal Resistance Junction-case | Max | 1.36 | °C/W |
| Rthj-amb | Thermal Resistance Junction-ambient | Max | 62.5 | °C/W |
| T _l | Maximum Lead Temperature For Soldering Purpose | Typ | 300 | °C |

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|----------------------|---|---|------|------|---------|----------|
| V _{(BR)DSS} | Drain-source Breakdown Voltage | I _D = 250 μA V _{GS} = 0 | 60 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current (V _{GS} = 0) | V _{DS} = Max Rating V _{DS} = Max Rating T _C = 125°C | | | 1 10 | μA μA |
| I _{GSS} | Gate-body Leakage Current (V _{DS} = 0) | V _{GS} = ± 20V | | | ±100 | nA |

ON (*)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------------|-----------------------------------|---|------|-------|-------|------|
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} = V _{GS} I _D = 250 μA | 2 | | 4 | V |
| R _{DS(on)} | Static Drain-source On Resistance | V _{GS} = 10 V I _D = 32 A | | 0.014 | 0.016 | Ω |

DYNAMIC

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--|---|---|------|--------------------|------|----------------|
| g _{fs} (*) | Forward Transconductance | V _{DS} = 25V I _D = 32 | 17 | | | S |
| C _{iss} C _{oss} C _{rss} | Input Capacitance Output Capacitance Reverse Transfer Capacitance | V _{DS} = 25V, f = 1 MHz, V _{GS} = 0 | | 1300 410 150 | | pF pF pF |

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--|--|---|------|----------------|------|----------------|
| t _{d(on)} t _r | Turn-on Delay Time Rise Time | V _{DD} = 30 V I _D = 32 A R _G = 4.7 Ω V _{GS} = 10 V (Resistive Load, Figure 3) | | 16 108 | | ns ns |
| Q _g Q _{gs} Q _{gd} | Total Gate Charge Gate-Source Charge Gate-Drain Charge | V _{DD} = 48V I _D = 65 A V _{GS} = 10V | | 49 18 14 | 66 | nC nC nC |

SWITCHING OFF

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------------------------------|----------------------------------|--|------|----------|------|----------|
| t _{d(off)} t _f | Turn-off Delay Time Fall Time | V _{DD} = 30 V I _D = 32 A R _G = 4.7Ω, V _{GS} = 10V (Resistive Load, Figure 3) | | 43 20 | | ns ns |

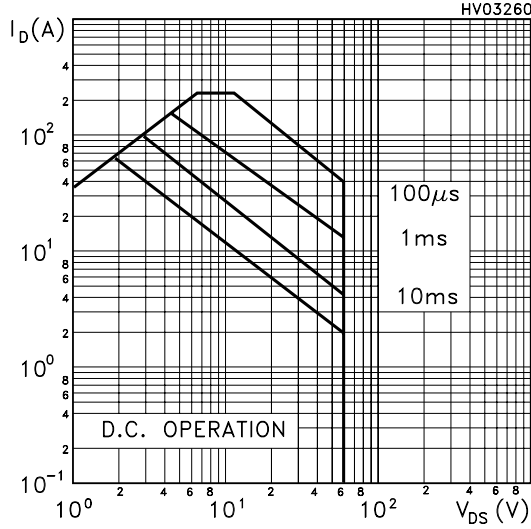
SOURCE DRAIN DIODE

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--|--|---|------|----------------|-----------|---------------|
| I _{SD} I _{SDM} (*) | Source-drain Current Source-drain Current (pulsed) | | | | 65 260 | A A |
| V _{SD} (*) | Forward On Voltage | I _{SD} = 65 A V _{GS} = 0 | | | 1.3 | V |
| t _{rr} Q _{rr} I _{RRM} | Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current | I _{SD} = 65 A di/dt = 100A/μs V _{DD} = 20 V T _j = 150°C (see test circuit, Figure 5) | | 73 182 5 | | ns nC A |

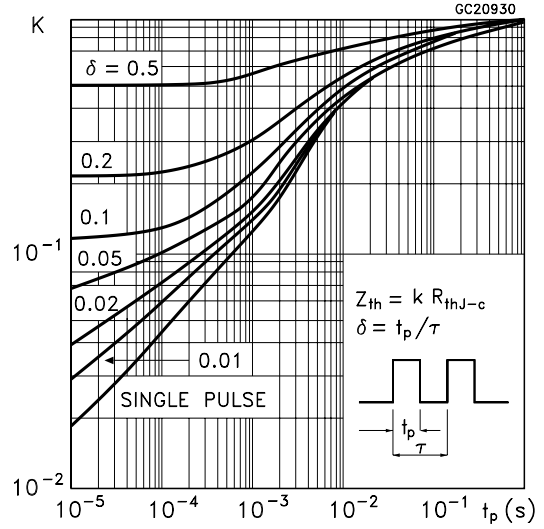
(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.

(●) Pulse width limited by safe operating area.

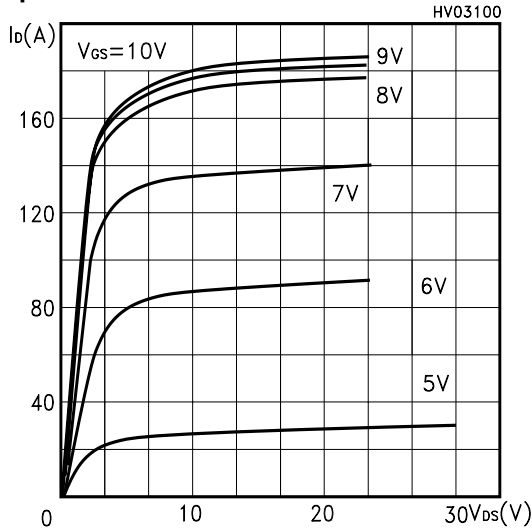
Safe Operating Area



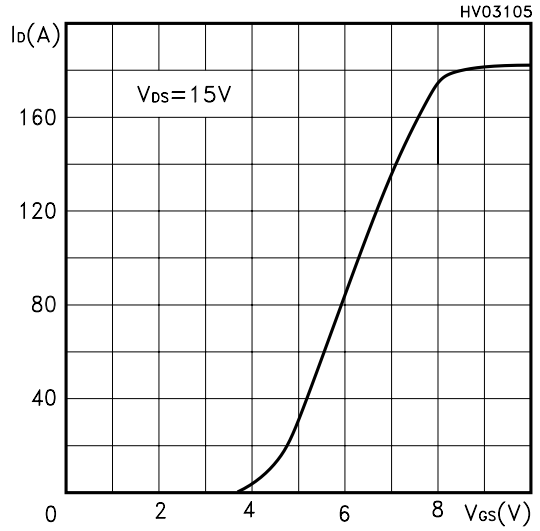
Thermal Impedance



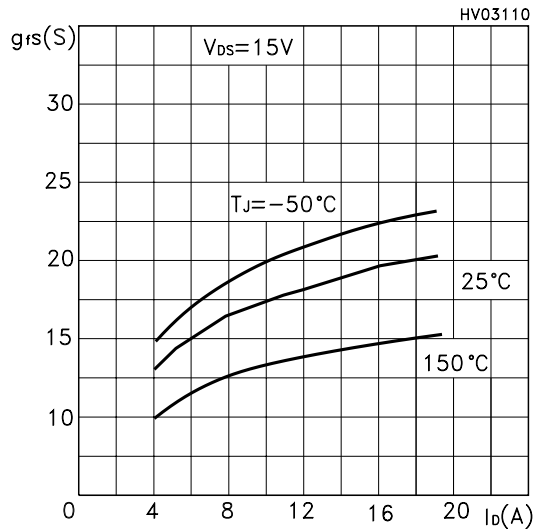
Output Characteristics



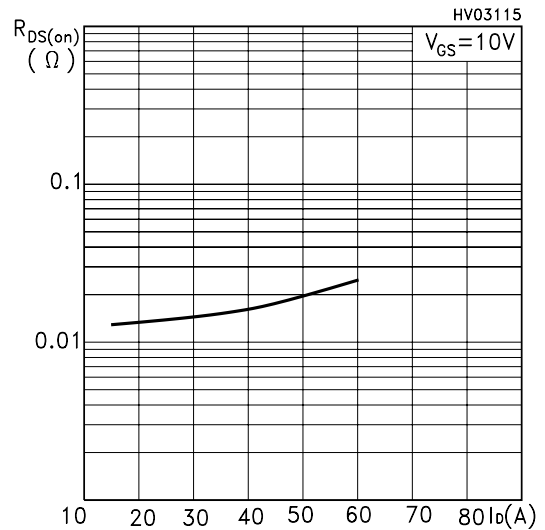
Transfer Characteristics



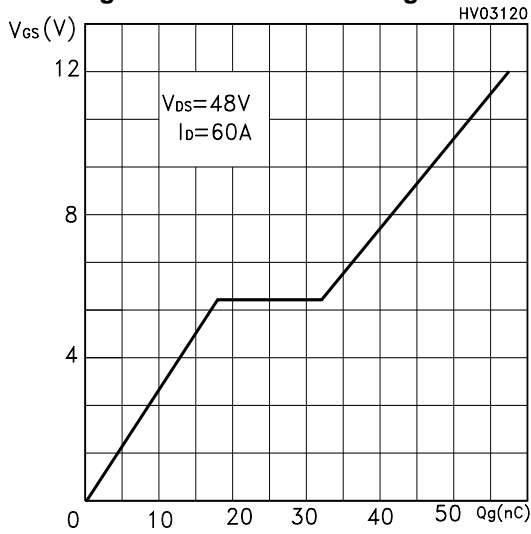
Transconductance



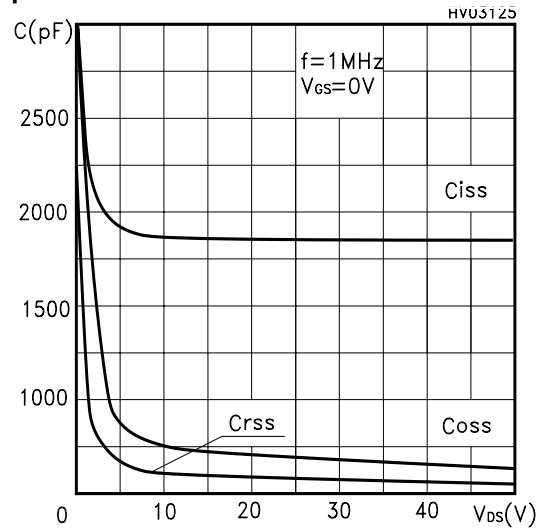
Static Drain-source On Resistance



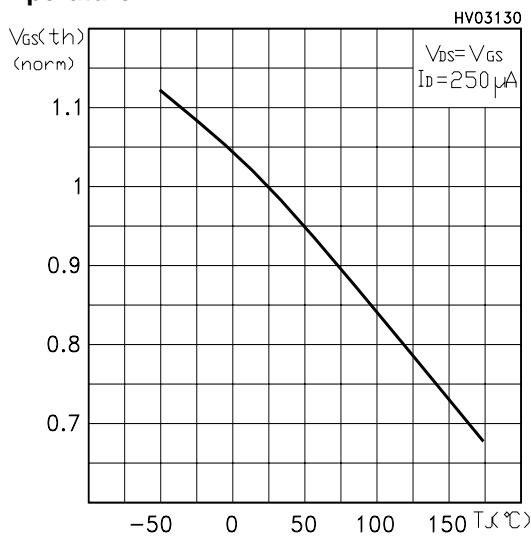
Gate Charge vs Gate-source Voltage



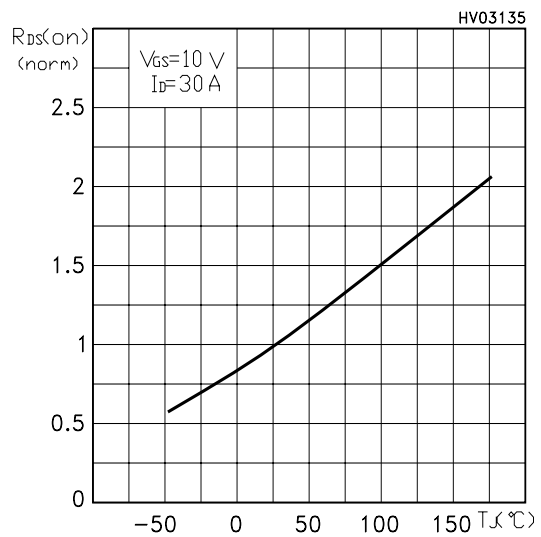
Capacitance Variations



Normalized Gate Threshold Voltage vs Temperature



Normalized On Resistance vs Temperature



Source-drain Diode Forward Characteristics

